

## High Current FET Driver

#### **FEATURES**

- Totem Pole Output with 6A Source/Sink Drive
- 3ns Delay
- 20ns Rise and Fall Time into 2.2nF
- 8ns Rise and Fall Time into 30nF
- 4.7V to 18V Operation
- Inverting and Non-Inverting Outputs
- Under-Voltage Lockout with Hysteresis
- Thermal Shutdown Protection
- MINIDIP and Power Packages

#### DESCRIPTION

The UC1710 family of FET drivers is made with a high-speed Schottky process to interface between low-level control functions and very high-power switching devices-particularly power MOSFET's. These devices accept low-current digital inputs to activate a high-current, totem pole output which can source or sink a minimum of 6A.

Supply voltages for both  $V_{IN}$  and  $V_{C}$  can independently range from 4.7V to 18V. These devices also feature under-voltage lockout with hysteresis.

The UC1710 is packaged in an 8-pin hermetically sealed dual in-line package for -55°C to +125°C operation. The UC2710 and UC3710 are specified for a temperature range of -40°C to +85°C and 0°C to +70°C respectively and are available in either an 8-pin plastic dual in-line or a 5-pin, TO-220 package. Surface mount devices are also available.

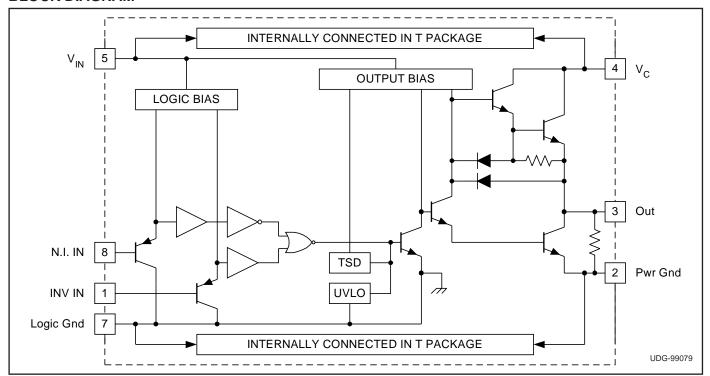
#### **ORDERING INFORMATION**

	TEMPERATURE RANGE	PACKAGE
UC1710J	-55°C to +125°C	8 pin CDIP
UC2710DW	-40°C to +85°C	16 pin SOIC-wide
UC2710J		8 pin CDIP
UC2710N		8 pin PDIP
UC2710T		5 pin TO220
UC3710DW	0°C to +70°C	16 pin SOIC-wide
UC3710N		8 pin PDIP
UC3710T		5 pin TO220

#### TRUTH TABLE

INV	N.I.	Out	
Н	Н	L	OUT= INV and N.I.
L	Н	Н	$\overline{OUT}$ = INV or $\overline{N.I.}$
Н	L	L	
L	L	L	

#### **BLOCK DIAGRAM**



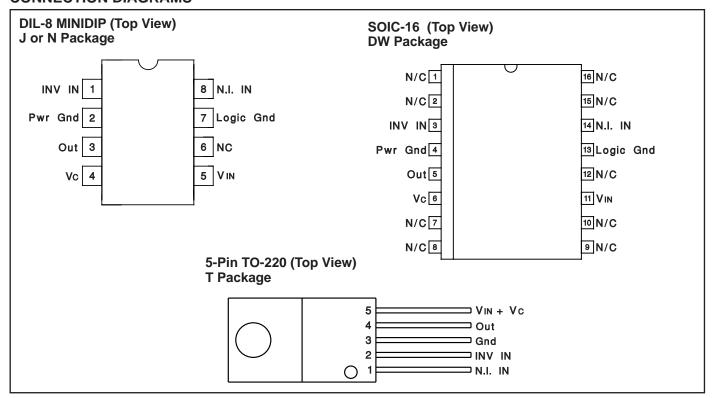
#### **ABSOLUTE MAXIMUM RATINGS**

	N-Package	J-Package	T-Package
Supply Voltage, Vin	20V	20V	20V
Collector Supply Voltage, V <sub>C</sub>	20V	20V	20V
Operating Voltage	18V	18V	18V
Output Current (Source or Sink)			
Steady-State	± 500mA.	± 500mA	± 1A
Digital Inputs	0.3V-VIN	0.3V - V <sub>IN</sub>	0.3V - VIN
Power Dissipation at Ta=25°C	1W .	1W	3W
Power Dissipation at T (Case) = 25°C	2W.	2W	25W
Operating Junction Temperature55	°C to +150°C.	55°C to +150°C	–55°C to +150°C
Storage Temperature65	°C to +150°C.	–65°C to +150°C	–65°C to +150°C
Lead Temperature (Soldering, 10 seconds)	300°C	300°C	300°C

Note 1: All currents are positive into, negative out of the specified terminal.

Note 2: Consult Unitrode Integrated Circuits databook for information regarding thermal specifications and limitations of packages.

#### **CONNECTION DIAGRAMS**



# **ELECTRICAL CHARACTERISTICS:** Unless otherwise stated, these specifications apply for $V_{IN} = V_C = 15V$ , No load, $T_A = T_{.I}$

PARAMETERS	TEST CONDITIONS	MIN	TYP	MAX	UNITS
V <sub>IN</sub> Supply Current	$V_{IN}$ =18V, $V_C$ =18V, Output Low		26	35	mA
	$V_{IN}$ =18V, $V_{C}$ =18V, Output High		21	30	mA
V <sub>C</sub> Supply Current	$V_{IN}$ =18V, $V_C$ =18V, Output Low		1.5	5.0	mA
	$V_{IN} = 18V$ , $V_C = 18V$ , Output High		5.0	8	mA
UVLO Threshold	V <sub>IN</sub> High to Low	3.8	4.1	4.4	V
	V <sub>IN</sub> Low to High	4.1	4.4	4.8	V

### $\textbf{ELECTRICAL CHARACTERISTICS:} \ \ \textbf{Unless otherwise stated, these specifications apply for } \ V_{IN} = V_{C} = 15 \text{V, No load,}$

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ΙΔ	=	- 1	-	

PARAMETERS	TEST CONDITIONS	MIN	TYP	MAX	UNITS
UVLO Threshold Hysteresis		0.1	0.3	0.5	V
Digital Input Low Level				0.8	V
Digital Input High Level		2.0			V
Digital Input Current	Digital Input = 0.0V	-70	-4.0		μΑ
Output High Sat., V <sub>C</sub> – V <sub>O</sub>	$I_{O} = -100 \text{mA}$		1.35	2.2	V
	I <sub>O</sub> = -6A		3.2	4.5	V
Output Low Sat., V <sub>O</sub>	I <sub>O</sub> = 100mA		0.25	0.6	V
	I <sub>O</sub> = 6A		3.4	4.5	V
Thermal Shutdown			165		°C
From Inv., Input to Output (Note 3, 4):					
Rise Time Delay	CL = 0		35	70	ns
	CL = 2.2nF		35	70	ns
	CL = 30nF		35	70	ns
10% to 90% Rise	CL = 0		20	40	ns
	CL = 2.2nF		25	40	ns
	CL = 30nF		85	150	ns
Fall Time Delay	CL = 0		35	70	ns
	CL = 2.2nF		35	70	ns
	CL = 30nF		35	80	ns
90% to 10% Fall	CL = 0		15	40	ns
	CL = 2.2nF		20	40	ns
	CL = 30nF		85	150	ns
From N.I. Input to Output (Note 3,4):		<u>.</u>			
Rise Time Delay	CL = 0		35	70	ns
	CL = 2.2nF		35	70	ns
	CL = 30nF		35	70	ns
10% to 90% Rise	CL = 0		20	40	ns
	CL = 2.2nF		25	40	ns
	CL = 30nF		85	150	ns
Fall Time Delay	CL = 0		35	70	ns
	CL = 2.2nF		35	70	ns
	CL = 30nF		35	80	ns
90% to 10% Fall	CL = 0		15	40	ns
	CL = 2.2nF		20	50	ns
	CL = 30nF		85	150	ns
Total Supply Current at 200kHz Input Switching Frequency	T <sub>A</sub> = 25°C (Note 5) CL = 0		30	40	mA

Note: 3. Delay measured from 50% input change to 10% output change.

Note: 4. Those parameters with CL = 30nF are not tested in production.

Note: 5. Inv. Input pulsed at 50% duty cycle with N.I. Input = 3V. or N.I. Input pulsed at 50% duty cycle with Inv. Input = 0V.

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